

Application/Control	No. Applicant(s Reexamina	s)/Patent under tion
10/624,932	TAUPIER I	ET AL.
Examiner	Art Unit	
Christopher J. Nich	ols, Ph.D. 1647	

SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
SEQ ID NO: 2 residues 372-389	3/10/2005	CJN	